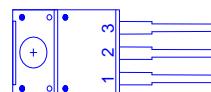
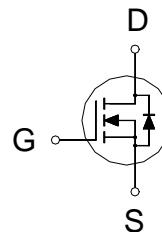


NIKO-SEM
**N-Channel Enhancement Mode
Field Effect Transistor**
P0270ATF(S)
TO-220F:P0270ATF
TO-220FS:P0270ATFS
Halogen-Free & Lead-Free
**PRODUCT SUMMARY**

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
700V	6.3Ω	2A


1. GATE
2. DRAIN
3. SOURCE
ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ C$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNITS
Gate-Source Voltage		V_{GS}	± 30	V
Continuous Drain Current ²	$T_C = 25^\circ C$	I_D	2	A
	$T_C = 100^\circ C$		1	
Pulsed Drain Current ¹		I_{DM}	8	
Avalanche Energy ³		E_{AS}	5	mJ
Power Dissipation	$T_C = 25^\circ C$	P_D	26	W
	$T_C = 100^\circ C$		10	
Operating Junction & Storage Temperature Range		T_j, T_{stg}	-55 to 150	°C

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Case	$R_{\theta JC}$	4.7	62.5	°C / W
Junction-to-Ambient	$R_{\theta JA}$			

¹Pulse width limited by maximum junction temperature.²Limited only by maximum temperature allowed³ $V_{DD} = 50V$, $L = 10mH$, starting $T_J = 25^\circ C$ **ELECTRICAL CHARACTERISTICS ($T_J = 25^\circ C$, Unless Otherwise Noted)**

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = 250\mu A$	700			V
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250\mu A$	2.5	3.8	4.5	
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0V, V_{GS} = \pm 30V$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 700V, V_{GS} = 0V$			25	μA
		$V_{DS} = 560V, V_{GS} = 0V, T_J = 125^\circ C$			250	
Drain-Source On-State Resistance ¹	$R_{DS(ON)}$	$V_{GS} = 10V, I_D = 1A$		5.5	6.3	Ω
Forward Transconductance ¹	g_{fs}	$V_{DS} = 10V, I_D = 1A$		1.5		S

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DYNAMIC						
Input Capacitance	C_{iss}	$V_{GS} = 0V, V_{DS} = 25V, f = 1MHz$		333		pF
Output Capacitance	C_{oss}			42		
Reverse Transfer Capacitance	C_{rss}			11		
Total Gate Charge ²	Q_g	$V_{DS} = 560V, V_{GS} = 10V, I_D = 2A$		6.5		nC
Gate-Source Charge ²	Q_{gs}			2		
Gate-Drain Charge ²	Q_{gd}			1.5		
Turn-On Delay Time ²	$t_{d(on)}$			30		
Rise Time ²	t_r	$V_{DD} = 350V, I_D \geq 2A, V_{GS} = 10V, R_{GS} = 25\Omega$		80		nS
Turn-Off Delay Time ²	$t_{d(off)}$			50		
Fall Time ²	t_f			70		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_J = 25^\circ C$)						
Continuous Current	I_S				2	A
Forward Voltage ¹	V_{SD}	$I_F = 2A, V_{GS} = 0V$			1.5	V
Reverse Recovery Time	t_{rr}	$I_S = 2A, dI_S/dt = 100A/\mu s$		356		nS
Reverse Recovery Charge	Q_{rr}			1.2		μC

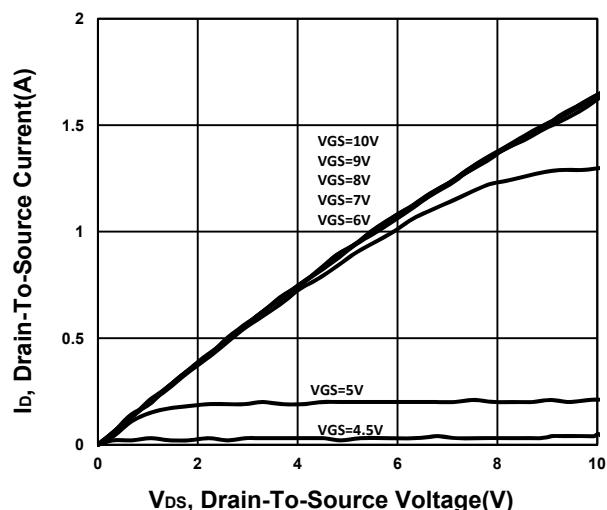
¹Pulse test : Pulse Width $\leq 300 \mu sec$, Duty Cycle $\leq 2\%$.²Independent of operating temperature.

NIKO-SEM

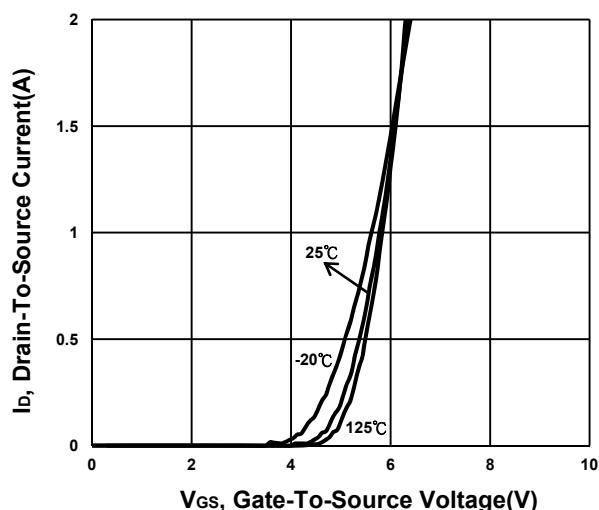
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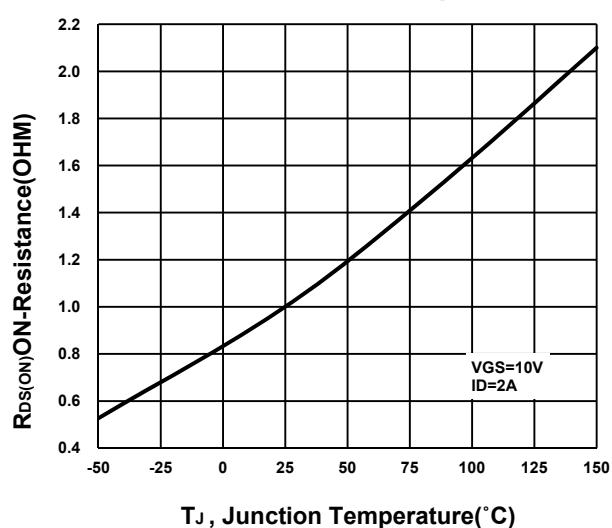
Output Characteristics



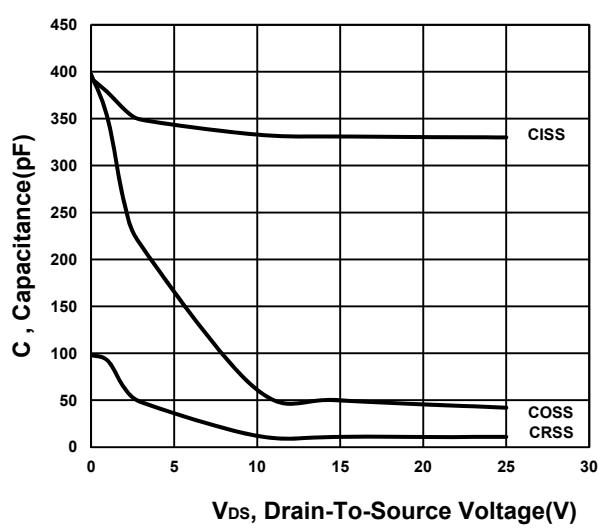
Transfer Characteristics



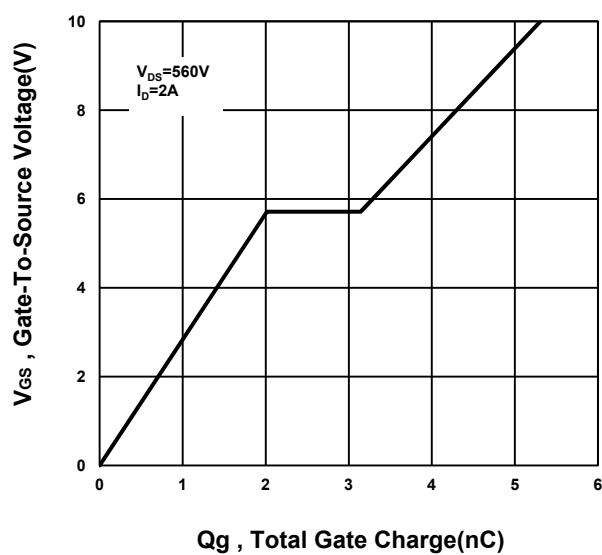
On-Resistance VS Temperature



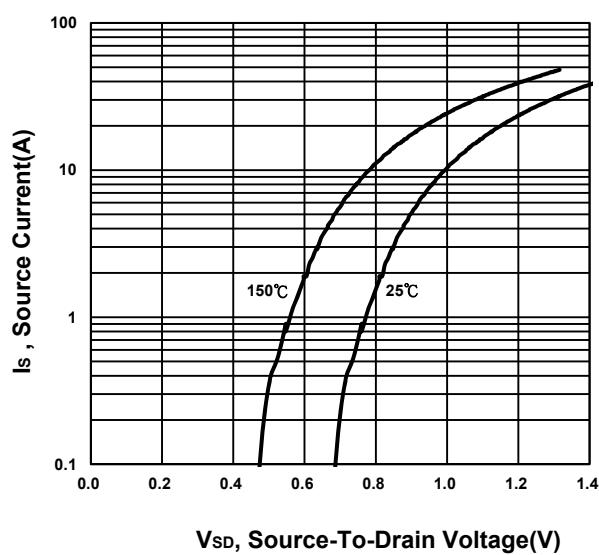
Capacitance Characteristic



Gate charge Characteristics



Source-Drain Diode Forward Voltage

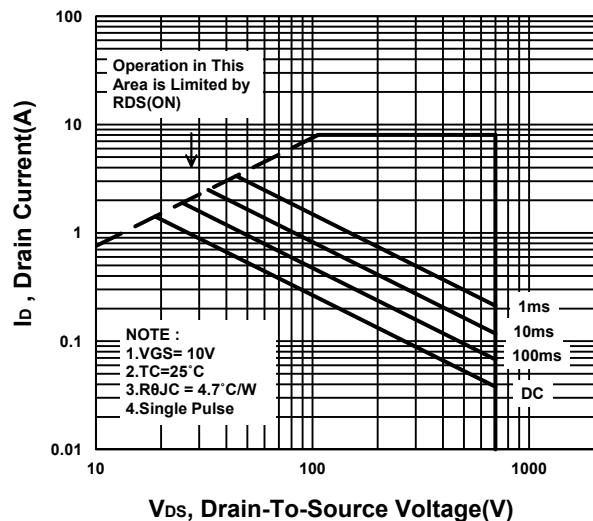


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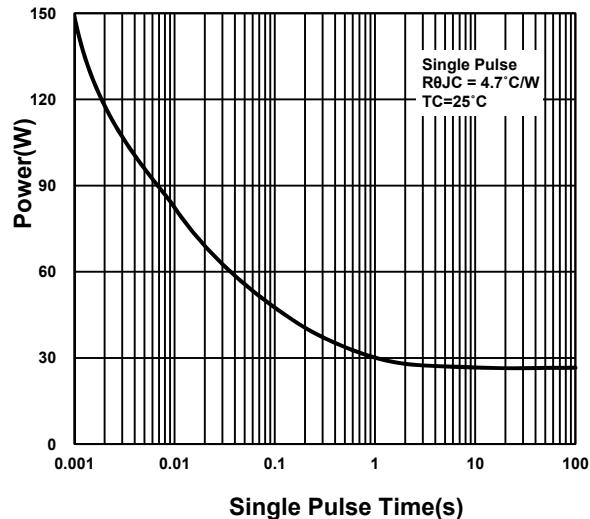
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Safe Operating Area



Single Pulse Maximum Power Dissipation



Transient Thermal Response Curve

